Amendments to the Claims:

1-14.   (Cancelled)

15.   (New) A method for testing memory, said method comprising: testing functional memory; repairing the memory by adding access to redundant elements; adding access to additional redundant memory which is not required for the repair; and after testing the functional memory and repairing the memory, testing the memory including the additional redundant memory which has been added which was not required for the repair.

16.   (New) A method as recited in claim 15, further comprising using repair information to repair the memory.

17.   (New) A method as recited in claim 15, wherein the step of adding access to additional redundant memory which is not required for the repair comprises forcing usage of redundant elements which are not needed to be used for repairing the memory.

18.   (New) A method as recited in claim 15, wherein the step of adding access to additional redundant memory which is not required for the repair comprises faking defects to remap good elements with redundant elements.

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19. (New) A method as recited in claim 15, further comprising checking interaction between redundant elements of the memory which are not used and adjacent functional memory.

20. (New) A method as recited in claim 15, further comprising forcing usage of all redundant elements, and determining whether a detected failure is associated with redundant elements.

21. (New) A mode for testing memory, said mode comprising: means for testing functional memory; repairing the memory by adding access to redundant elements; means for adding access to additional redundant memory which is not required for the repair; and means for, after testing the functional memory and repairing the memory, testing the memory including the additional redundant memory which has been added which was not required for the repair.

22. (New) A mode as recited in claim 21, further comprising means for using repair information to repair the memory.

23. (New) A mode as recited in claim 21, further comprising means for forcing usage of redundant elements which are not needed to be used for repairing the memory.

24. (New) A mode as recited in claim 21, further comprising means for faking defects to remap good elements with redundant elements.

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25.   (New) A mode as recited in claim 21, further comprising means for checking interaction

between redundant elements of the memory which are not used and adjacent functional memory.

26.   (New) A mode as recited in claim 21, further comprising means for forcing usage of all

redundant elements, and determining whether a detected failure is associated with redundant

elements.

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